

Title of Change:	Dual source AR0144 for Assembly and Final Test at ASE (Advanced Semiconductor Engineering Malaysia.					
Proposed Changed Material First Ship Date:	01 Sep 2023 or earlier if approved by customer					
Current Material Last Order Date:	N/A Orders received after the Current Material Last Order Date expiration are to be considered as orders for new changed material as described in this PCN. Orders for current (unchanged) material after this date will be per mutual agreement and current material inventory availability.					
Current Material Last Delivery Date:	N/A The Current Material Last Delivery Date may be subject to change based on build and depletion of the current (unchanged) material inventory					
Product Category:	Active components – Integrated circuits					
Contact information:	Contact your local onsemi Sales Office or Mike.Webster@onsemi.com					
PCN Samples Contact:	Contact your local onsemi Sales Office to place sample order. Sample requests are to be submitted no later than 45 days after publication of this change notification. Samples delivery timing will be subject to request date, sample quantity and special customer packing/label requirements.					
Sample Availability Date:	20 Mar 2023					
PPAP Availability Date:	27 Feb 2023					
Additional Reliability Data:	Contact your local onsemi Sales Office or <u>Amy.Wu@onsemi.com</u>					
Type of Notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. The change will be implemented at 'Proposed Change Material First Ship Date' in compliance to J-STD-46 or ZVEI, or earlier upon customer approval, or per our signed agreements. onsemi will consider this proposed change and it's conditions acceptable, unless an inquiry is made in writing within 45 days of delivery of this notice. To do so, contact <u>PCN.Support@onsemi.com</u> .					
Change Category						
Category	Type of Change					
Test Flow	Move of all or part of electrical wafer test and/or final test to a different location/site/subcontractor					
Equipment	Production from a new equipment/tool which uses the same basic technology (replacement equipment or extension of existing equipment pool) without change of process.					

# Description and Purpose:

Process - Assembly

ASEM (Advanced Semicondutor Engineering Malaysia) is being qualified and added as an additional site for Assembly and Final test for AR0144 packages.

Change of direct material supplier

equipment or extension of existing equipment pool) without change of process. Move of all or part of assembly to a different location/site/subcontractor.,

This is being done to add capacity and mitigate supply chain risks.

The assembly equipment between the sites are equivalent and have been proven on other dual-sourced automotive products.

ASEM will use a different substrate supplier than Kingpak but substrate design is exactly the same.

Product assembled at Tong Hsing (Kingpak) and ASEM can final test at any of the qualified Final Test sites.

There is no change in the test platform, program or limits between the two sites.



Final Product/Process Change Notification Document #: FPCN24557ZB Issue Date: 12 Jan 2023

			From			То			
	Assembly Site		Ton	g Hsing	Tong Hsin	g & ASE Mala	ysia		
Final Test Site						ing, KYEC & ASE Malaysia			
	Packago Substrato		Supplie	r - Eastorn	Supplier = Eastern (at Tong Hsing)				
Package Substrate Su			Supplie	r = Eastern	Supplier	= SCC (at ASEI	M)		
here is no pr	oduct marking change as	a result of	this change						
eason / Mo	otivation for Change:	Capacity	improvement						
unction, rel	impact on fit, form, iability, product nufacturability:	successfu performe	ully passed the qua	d and validated based on t lification tests. Potential i ion to the PCN, associated i	mpacts can be id	entified, but			
ites Affecte	ed:								
onsemi Sites				External Foundry/Subcon Sites					
lone				ASEM, Malaysia					
-	Parts/ Traceability of	Lot histo	ory; Unique shipping	label					
Change: Reliability D	ata Summary: AME : AR0144AT ISG (external qual)	Lot histo	ory; Unique shipping	label					
change: celiability D QV DEVICE N/ cMS: n/a for ACKAGE : iB	ata Summary: AME : AR0144AT ISG (external qual) GA	Lot histo	ory; Unique shipping	label		Interval	Results		
hange: eliability D V DEVICE N/ MS: n/a for	ata Summary: AME : AR0144AT ISG (external qual)	Lot histo		Condition	Vcc	Interval 1008 hrs			
hange: eliability D V DEVICE N/ MS: n/a for ACKAGE : iB Test HTOL	ata Summary: AME : AR0144AT ISG (external qual) ISGA Specification JESD22-A108	Lot histo		Condition 05_°C Tj, 100 % max rated	Vcc		<b>Results</b> 0/231 0/2400		
hange: eliability D V DEVICE N/ MS: n/a for ACKAGE : iB Test	ata Summary: AME : AR0144AT ISG (external qual) IGA Specification			Condition	/cc	1008 hrs	0/231		
hange: eliability D V DEVICE N/ MS: n/a for ACKAGE : iB Test HTOL ELFR	ata Summary: AME : AR0144AT ISG (external qual) ISGA Specification JESD22-A108 AEC Q100-008			Condition 05_°C Tj, 100 % max rated Ta= <u>125</u> °C	Vcc	1008 hrs	0/231 0/2400		
Change: Celiability D CV DEVICE N/ MS: n/a for ACKAGE : iB Test HTOL ELFR PC	ata Summary: AME : AR0144AT ISG (external qual) ISGA Specification JESD22-A108 AEC Q100-008 J-STD-020 JESD-A1			Condition 05_°C Tj, 100 % max rated <sup>v</sup> Ta= <u>125</u> °C MSL 3 @ 260 °C	/cc	1008 hrs 24 hrs	0/231 0/2400 Pass		
Change: Celiability D CV DEVICE N/ MS: n/a for ACKAGE : iB Test HTOL ELFR PC HTSL	ata Summary: AME : AR0144AT ISG (external qual) ISGA Specification JESD22-A108 AEC Q100-008 J-STD-020 JESD-A1 JESD22-A103			Condition   05_°C Tj, 100 % max rated '   Ta= 125 °C   MSL 3 @ 260 °C   Ta= 150 °C	Vcc	1008 hrs 24 hrs 500 hrs 1000 cyc 264 hrs	0/231 0/2400 Pass 0/45		
Change: Celiability D CV DEVICE N/ CMS: n/a for ACKAGE : iB Test HTOL ELFR PC HTSL TC	ata Summary: AME : AR0144AT ISG (external qual) ISGA Specification JESD22-A108 AEC Q100-008 J-STD-020 JESD-A1 JESD22-A103 JESD22-A104			Condition   05 °C Tj, 100 % max rated <sup>1</sup> Ta= 125 °C   MSL 3 @ 260 °C °C   Ta= 150 °C   Ta= 55 °C to +125	Vcc	1008 hrs 24 hrs 500 hrs 1000 cyc	0/231 0/2400 Pass 0/45 0/231		
change: celiability D CV DEVICE N/ cMS: n/a for ACKAGE : iB Test HTOL ELFR PC HTSL TC HAST	ata Summary: AME : AR0144AT ISG (external qual) ISGA Specification JESD22-A108 AEC Q100-008 J-STD-020 JESD-A1 JESD22-A103 JESD22-A104 JESD22-A110 JESD22-A118 AEC Q100-001			Condition   05_°C Tj, 100 % max rated 1   Ta= 125 °C   MSL 3 @ 260 °C   Ta= 150 °C   Ta= 255 °C to +125 °C   130°C, 85% RH, with bias	Vcc 1	1008 hrs 24 hrs 500 hrs 1000 cyc 264 hrs	0/231 0/2400 Pass 0/45 0/231 0/231		
hange: eliability D V DEVICE N/ MS: n/a for ACKAGE : iB Test HTOL ELFR PC HTSL TC HAST UHAST	ata Summary: AME : AR0144AT ISG (external qual) ISGA Specification JESD22-A108 AEC Q100-008 J-STD-020 JESD-A1 JESD22-A103 JESD22-A110 JESD22-A110 JESD22-A118	.13	Ta= <u>1</u>	Condition   05 °C Tj, 100 % max rated '   Ta= 125 °C   MSL 3 @ 260 °C   Ta= 150 °C   Ta= -55 °C to +125 °C   130°C, 85% RH, with bias   130°C, 85% RH, unbiased		1008 hrs 24 hrs 500 hrs 1000 cyc 264 hrs	0/231 0/2400 Pass 0/45 0/231 0/231		
hange: eliability D V DEVICE N/ MS: n/a for ACKAGE : iB Test HTOL ELFR PC HTSL TC HAST UHAST WBS	ata Summary: AME : AR0144AT ISG (external qual) ISGA Specification JESD22-A108 AEC Q100-008 J-STD-020 JESD-A1 JESD22-A103 JESD22-A104 JESD22-A110 JESD22-A118 AEC Q100-001 AEC Q003 MIL-STD883 Method	.13	Ta= <u>1</u>	Condition   05 °C Tj, 100 % max rated '   Ta= 125 °C   MSL 3 @ 260 °C   Ta= 150 °C   Ta= <u>155</u> °C to +125 °C   130°C, 85% RH, with bias   130°C, 85% RH, unbiased   CPK >1.67		1008 hrs 24 hrs 500 hrs 1000 cyc 264 hrs	0/231 0/2400 Pass 0/45 0/231 0/231 0/231 Pass		
hange: eliability D V DEVICE N/ MS: n/a for ACKAGE : iB Test HTOL ELFR PC HTSL TC HAST UHAST WBS WBP	ata Summary: AME : AR0144AT ISG (external qual) ISGA Specification JESD22-A108 AEC Q100-008 J-STD-020 JESD-A1 JESD22-A103 JESD22-A104 JESD22-A110 JESD22-A118 AEC Q100-001 AEC Q003 MIL-STD883 Method AEC Q003	.13	Та=_1	Condition 05_°C Tj, 100 % max rated <sup>™</sup> Ta= <u>125</u> °C MSL 3 @ 260 °C Ta= <u>150</u> °C Ta= <u>-55</u> °C to <u>+125</u> °C 130°C, 85% RH, with bias 130°C, 85% RH, unbiased CPK >1.67 L.67, 0 Fails after TC (test #	A4)	1008 hrs 24 hrs 500 hrs 1000 cyc 264 hrs	0/231 0/2400 Pass 0/45 0/231 0/231 0/231 Pass Pass		
change: celiability D ty DEVICE N/ MS: n/a for ACKAGE : iB Test HTOL ELFR PC HTSL TC HAST UHAST WBS WBP HBM	ata Summary: AME : AR0144AT ISG (external qual) ISGA Specification JESD22-A108 AEC Q100-008 J-STD-020 JESD-A1 JESD22-A103 JESD22-A104 JESD22-A104 JESD22-A110 JESD22-A118 AEC Q100-001 AEC Q003 MIL-STD883 Method AEC Q100-002	.13	Та=_1	Condition   05 °C Tj, 100 % max rated '   Ta= 125 °C   MSL 3 @ 260 °C   Ta= 150 °C   Ta= -55 °C to +125 °C   130°C, 85% RH, with bias   130°C, 85% RH, unbiased   CPK >1.67   L.67, 0 Fails after TC (test #   0 Fails; 2KV HBM	A4)	1008 hrs 24 hrs 500 hrs 1000 cyc 264 hrs	0/231 0/2400 Pass 0/45 0/231 0/231 0/231 Pass Pass Pass		

### Note: AEC-1pager is attached.

To view attachments:

1. Download pdf copy of the PCN to your computer

2. Open the downloaded pdf copy of the PCN

3. Click on the paper clip icon available on the menu provided in the left/bottom portion of the screen to reveal the Attachment field

4. Then click on the attached file.



## Final Product/Process Change Notification Document #: FPCN24557ZB Issue Date: 12 Jan 2023

## **Electrical Characteristics Summary:**

AR0144 test data at Ta	=room temp		USL (RT)	Units	Upper	Tong Hsing		ASEM		Accuracy%	Temp Condition		
Quantity	Mode			Onito	Specification	Stdev	Mean	CPK	Stdev	Mean	CPK	/ 10001009 /0	of specification
D6_PIX_BRT	Dark	0	80	Pixels	80	1.697	1.867	n/a	1.800	2.000	n/a	7.143	Tj=60
M6_PIX_BRT	Midlight	0	79	Pixels	79	0.461	0.167	n/a	0.434	0.133	n/a	20.000	Tj=60
M7_PIX_DRK	Midlight	0	79	Pixels	79	0.610	0.200	n/a	0.484	0.200	n/a	0.000	Tj=60
M3_CLUS_BRT	Midlight	0	9	Clusters	9	0.000	0.000	n/a	0.000	0.000	n/a	0.000	Tj=60
M4_CLUS_DRK	Midlight	0	9	Clusters	9	0.000	0.000	n/a	0.000	0.000	n/a	0.000	Tj=60
la_OPER_VAA	Short	45	72	mA	72	1.527	59.467	2.735	1.581	59.547	2.625	0.135	Tj=60
Ip_OPER_VAA_PIX	Short	1	50	mA	50	0.196	9.199	13.974	0.200	9.202	13.661	0.031	Tj=60
Id_OPER_VDD	Short	90	120	mA	120	1.404	107.696	2.922	1.220	110.376	2.630	2.488	Tj=60
li_OPER_VDD_PLL	Short	1	50	mA	50	0.063	6.838	30.889	0.086	6.892	22.948	0.788	Tj=60
Mh_PVAL_MEAN	Midlight	1800	2600	code	2600	41.660	2147.635	2.782	38.395	2187.172	3.361	1.841	Tj=60
Dh_PVAL_MEAN	Dark	150	180	code	180	2.104	166.729	2.103	0.907	166.772	4.863	0.026	Tj=60

Electrical characteristics are not impacted.

### List of Affected Parts:

**Note:** Only the standard (off the shelf) part numbers are listed in the parts list. Any custom parts affected by this PCN are shown in the customer specific PCN addendum in the PCN email notification, or on the <u>PCN Customized Portal</u>.

Current Part Number	New Part Number	Qualification Vehicle			
AR0144ATSM20XUEA0-SP-TPBR	NA	AR0144ATSM20XUEA0-DRBR			
AR0144ATSM20XUEA0-TRBR	NA	AR0144ATSM20XUEA0-DRBR			
AR0144ATSM20XUEA0-TPBR	NA	AR0144ATSM20XUEA0-DRBR			
AR0144ATSM20XUEA0-DPBR	NA	AR0144ATSM20XUEA0-DRBR			
AR0144ATSM20XUEA0-DRBR	NA	AR0144ATSM20XUEA0-DRBR			

# Appendix A: Changed Products

## DIKG: DIGI-KEY

Product	Customer Part Number	Qualification Vehicle	New Part Number	Replacement Supplier
AR0144ATSM20XUEA0-DPBR		AR0144ATSM20XUEA0-DRBR	NA	
AR0144ATSM20XUEA0-DRBR		AR0144ATSM20XUEA0-DRBR	NA	